

FISCHERSCOPE® X-RAY XAN® 220 FISCHERSCOPE® X-RAY XAN® 222

X-Ray Fluorescence Measuring Instruments for fast and non-destructive Analysis and Coating Thickness Measurement of Gold and Silver Alloys



Description

The FISCHERSCOPE X-RAY XAN 220 and XAN 222 are optimized X-ray fluorescence measuring instruments for non-destructive analysis of jewelry, coins and precious metals.

They are particularly suited for the analysis of precious metals and their alloys in composition and coating thickness. Up to 24 elements can be determined simultaneously.

Typical fields of application are the analysis of:

- Jewelry, precious metals and dental alloys
- Yellow and white gold
- Platinum and silver
- Rhodium
- Alloys and coatings
- Multi layer coatings

Outstanding accuracy and long-term stability are characteristics of all FISCHERSCOPE X-RAY systems. The necessity of recalibration is dramatically reduced, saving time and effort.

The modern silicon drift detector achieves high accuracy and good detection sensitivity.

The fundamental parameter method by FISCHER allows for the analysis of solid and liquid specimens as well as coating systems without calibration.

Design

The XAN 220 and XAN 222 are designed as user-friendly bench-top instruments. They differ in the support stage and the housing size:

- XAN 220: Fixed sample support
- XAN 222: Manually operable XY stage for accurate positioning of small parts and larger measuring chamber

For quick and easy sample positioning, the X-ray source and semiconductor detector assembly is located in the instrument's lower chamber. The measuring direction is from underneath the sample, which is supported by a transparent window.

The integrated video-microscope with zoom and crosshairs simplifies sample placement and allows precise measuring spot adjustment.

The entire operation and evaluation of measurements as well as the clear presentation of measurement data is performed on a PC, using the powerful and user-friendly WinFTM® software.

The FISCHERSCOPE X-RAY XAN 220 and XAN 222 fulfill DIN ISO 3497 and ASTM B 568. The XAN 220 is a fully protected instrument with type approval according to the German regulations „Deutsche Röntgenverordnung-RöV“.

General Specification

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|---------------------|--|
| Intended use | Energy dispersive X-ray measuring instrument (EDXRF) to analyze precious metals and their alloys in composition and coating thickness. |
| Element range | Sulfur (16) to Uranium (92) – up to 24 elements simultaneously |
| Repeatability | ≤ 0.5 ‰ for gold, measurement time 60 sec |
| Design | Bench top unit with upwards opening hood |
| Measuring direction | Bottom up |

X-Ray Source

| | |
|-----------------------|---|
| X-ray tube | Micro-focus tungsten tube with beryllium window |
| High voltage | Three steps: 30 kV, 40 kV, 50 kV |
| Aperture (Collimator) | Ø 1 mm (39 mils), optional Ø 2 mm (79 mils) or Ø 0.6 mm (23.6 mils) |
| Measurement spot | Ø 1.2 mm (47 mils) with aperture Ø 1 mm (39 mils) and flat lying sample (measurement distance 0 mm) |

X-Ray Detection

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|--|--|
| X-ray detector | Silicon Drift Detector (SDD), peltier-cooled |
| Resolution (fwhm for Mn-K _α) | ≤ 160 eV |
| Measuring distance | 0 ... 25 mm (0 ... 1 in) Distance compensation with patented DCM method for simplified measurements at varying distances. For particular applications or for higher demands on accuracy an additional calibration might be necessary. |

Sample Alignment

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|--------------------|---|
| Sample positioning | Manually |
| Video microscope | High-resolution CCD color camera for optical monitoring of the measurement location along the primary beam axis, Crosshairs with a calibrated scale (ruler) and spot-indicator, Adjustable LED illumination |
| Zoom factor | Digital 1x, 2x, 3x, 4x |

Sample Stage

| | XAN 220 | XAN 222 |
|------------------------------|-------------------------------|----------------------------|
| Design | Fixed sample support | Manually operable XY stage |
| Usable sample placement area | 310 x 320 mm (12.2 x 12.6 in) | |
| Max. sample weight | 13 kg (29 lb) | 2 kg (4.4 lb) |
| Max. sample height | 90 mm (3.5 in) | 174 mm (6.8 in) |

Electrical data

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|-------------------|-----------------------------------|
| Power supply | AC 115 V or AC 230 V 50 / 60 Hz |
| Power consumption | max. 120 W, without evaluation PC |
| Protection class | IP40 |

FISCHERSCOPE[®] X-RAY XAN[®] 220/222

Dimensions

| | XAN 220 | XAN 222 |
|------------------------|-----------------------|-----------------------|
| External dimensions | 403 x 588 x 365 mm | 403 x 588 x 444 mm |
| Width x depth x height | (16 x 23.2 x 14.4 in) | (16 x 23.2 x 17.5 in) |
| Weight | Approx. 45 kg (99 lb) | |

Environmental Conditions

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|-------------------------------|--------------------------------|
| Operating temperature | 10 °C – 40 °C / 50 °F – 104 °F |
| Storage/Transport temperature | 0 °C – 50 °C / 32 °F – 122 °F |
| Admissible air humidity | ≤ 95 %, non-condensing |

Evaluation unit

| | |
|----------|---|
| Computer | Windows [®] -PC |
| Software | Standard: Fischer WinFTM [®] BASIC including PDM [®] , Optional: Fischer WinFTM [®] SUPER |

Standards

| | XAN 220 | XAN 222 |
|-----------------|---|--|
| CE approval | EN 61010 | |
| X-Ray standards | DIN ISO 3497 and ASTM B 568 | |
| Approval | Fully protected instrument with type approval according to the German regulations „Deutsche Röntgenverordnung-RöV“. | Individual acceptance inspection as a fully protected instrument according to the German regulations „Deutsche Röntgenverordnung-RöV“. |

Order

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|----------------------------|-----------|
| FISCHERSCOPE X-RAY XAN 220 | 604-771 * |
| FISCHERSCOPE X-RAY XAN 222 | 604-772 * |

* Includes the Gold Setup 604-512, which contains all calibrated measurement applications necessary for the analysis of jewellery, coins and precious metals
Special XAN product modification and technical consultation on request

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